Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/685,514	WEIK ET AL.	
	Examiner	Art Unit	
	Benny Q. Tieu	2614	

SEARCHED			
Class	Subclass	Date	Examiner
379	219 220.01 221.01 221.08- 221.1	12/21/2006	BQT
	221.15		
	229 230		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	12/21/2006	BQT